

STB200N04

N-channel 40V - 0.0035Ω - 120A - D²PAK Planar STripFET™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D	P _w
STB200N04	40V	<0.0040Ω	120A	300W

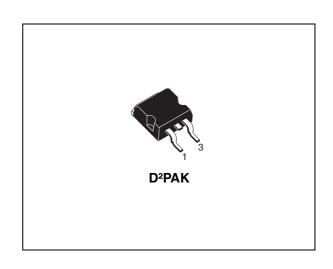
- 100% avalanche tested
- Standard threshold drive

Description

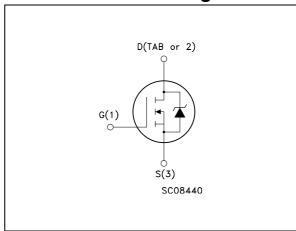
This Power MOSFET is the latest development of STMicroelectronics unique "single feature size™" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility. this new improved device has been specifically designed for automotive applications.

Applications

- Switching application
 - Automotive



Internal schematic diagram



Order codes

Part number	Marking	Marking Package	
STB200N04	B200N04	D ² PAK	Tape & reel

Contents STB200N04

Contents

1	Electrical ratings	. 3
2	Electrical characteristics	
3	Test circuit	
4	Package mechanical data	. 9
5	Packaging mechanical data	11
6	Revision history	12

STB200N04 Electrical ratings

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	40	V
V _{GS}	Gate-source voltage	±20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25°C	120	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100°C	120	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	480	Α
P _{TOT}	Total dissipation at T _C = 25°C	300	W
	Derating factor	2.0	W/°C
E _{AS} (3)	Single pulse avalanche energy	862	mJ
dv/dt ⁽⁴⁾	Peak diode recovery voltage slope	4.2	V/ns
T _j T _{stg}	Operating junction temperature Storage temperature -55 to 175		

- 1. Current limited by package
- 2. Pulse width limited by safe operating area
- 3. Starting Tj = 25° C, $I_D = 60$ A, $V_{DD} = 25$ V
- 4. $I_{SD} \leq 60A$, di/dt ≤ 440 A/ μ s, $V_{DD} \leq V_{(BR)DSS}$, $T_j \leq T_{JMAX}$.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case max	0.50	°C/W
Rthj-pcb (1)	Thermal resistance junction-pcb max	35	°C/W

1. When mounted on FR-4 board, 1inch² 2 oz Cu

Electrical characteristics STB200N04

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	40			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = Max rating,$ $V_{DS} = Max rating @ 125°C$			10 100	μ Α μ Α
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2		4	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 80A		0.0035	0.0040	Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} =10V, I _D = 80A		200		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1 MHz, V _{GS} =0		5100 1270 37		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =20V, I_{D} = 120A V_{GS} =10V (see Figure 13)		75 23 17		nC nC nC

^{1.} Pulsed: pulse duration=300µs, duty cycle 1.5%

Table 5. Switching times

Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
t _{d(on)}	Turn-on delay time Rise time	V_{DD} =20 V, I_D =60A, R_G =4.7 Ω , V_{GS} =10V (see Figure 12)		19 180		ns ns
t _{d(off)}	Off-voltage rise time Fall time	V_{DD} =20 V, I_D =60A, R_G =4.7 Ω , V_{GS} =10V (see Figure 12)		90 65		ns ns

Table 6. Source drain diode

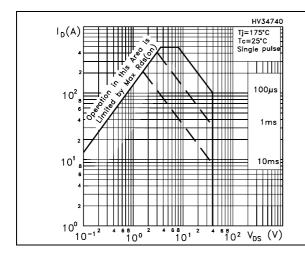
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				120 480	A A
V _{SD}	Forward on voltage	I _{SD} =120A, V _{GS} =0			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} =120A, di/dt = 100A/ μ s, V_{DD} =20 V, Tj=150°C (see Figure 17)		67 130 4		ns nC A

Electrical characteristics STB200N04

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance



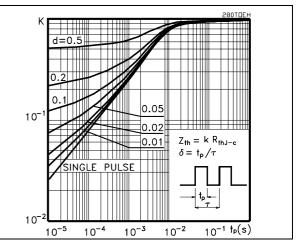
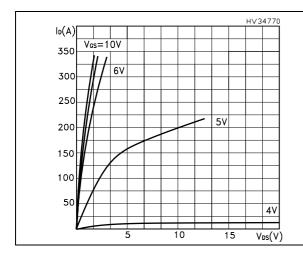


Figure 3. Output characteristics

Figure 4. Transfer characteristics



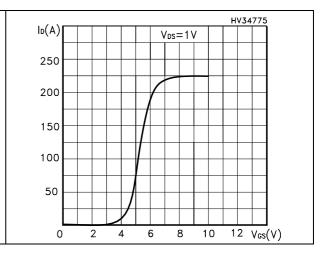
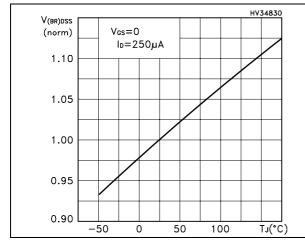
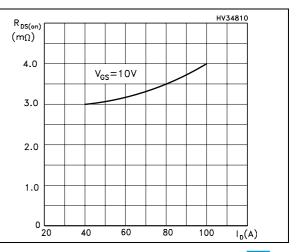


Figure 5. Normalized B_{VDSS} vs temperature

Figure 6. Static drain-source on resistance





57

Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

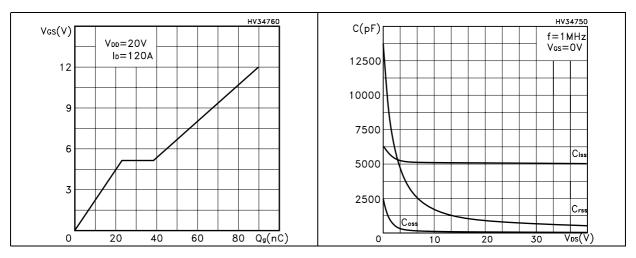


Figure 9. Normalized gate threshold voltage Figure 10. Normalized on resistance vs vs temperature temperature

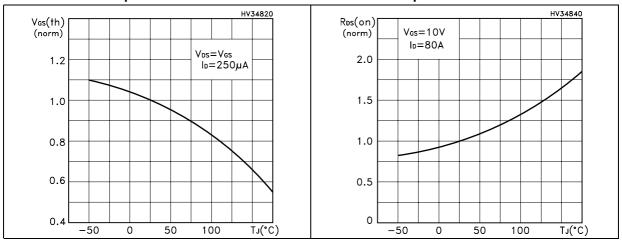
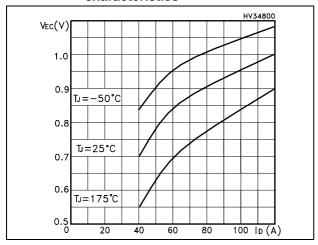


Figure 11. Source-drain diode forward characteristics



57

Test circuit STB200N04

3 Test circuit

Figure 12. Switching times test circuit for resistive load

Figure 13. Gate charge test circuit

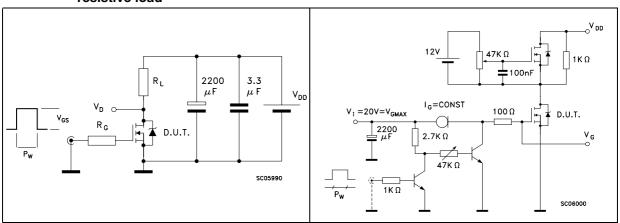


Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit

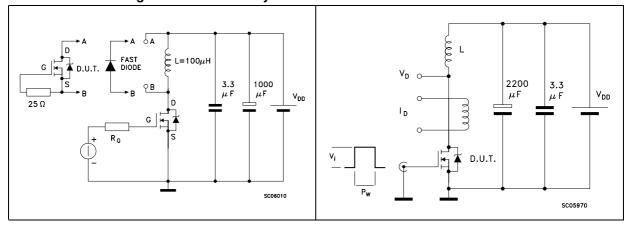
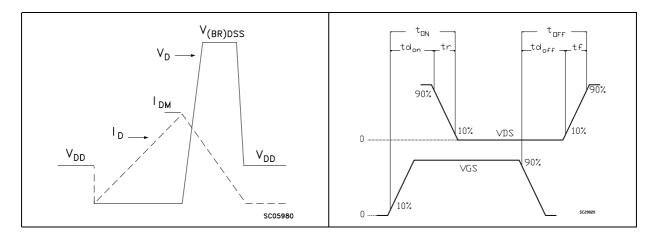


Figure 16. Unclamped inductive waveform

Figure 17. Switching time waveform



47/

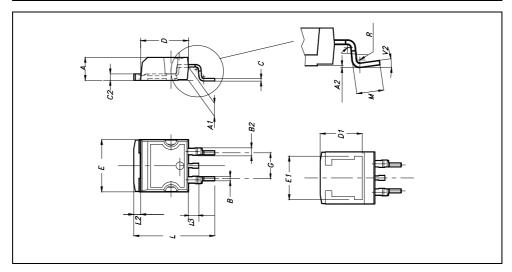
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

9/13

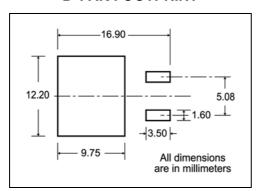
D²PAK MECHANICAL DATA

DIM.		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.4		4.6	0.173		0.181
A1	2.49		2.69	0.098		0.106
A2	0.03		0.23	0.001		0.009
В	0.7		0.93	0.027		0.036
B2	1.14		1.7	0.044		0.067
С	0.45		0.6	0.017		0.023
C2	1.23		1.36	0.048		0.053
D	8.95		9.35	0.352		0.368
D1		8			0.315	
E	10		10.4	0.393		
E1		8.5			0.334	
G	4.88		5.28	0.192		0.208
L	15		15.85	0.590		0.625
L2	1.27		1.4	0.050		0.055
L3	1.4		1.75	0.055		0.068
М	2.4		3.2	0.094		0.126
R		0.4			0.015	
V2	00		4º			

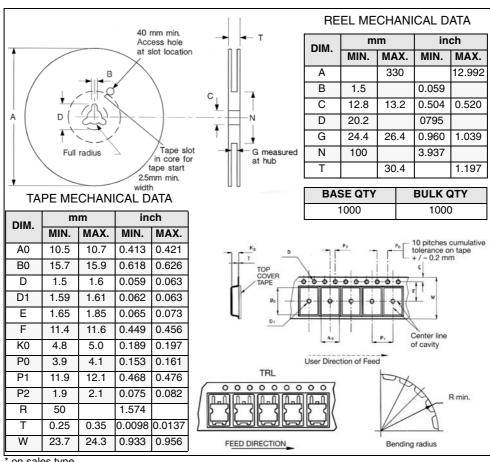


Packaging mechanical data 5

D²PAK FOOTPRINT



TAPE AND REEL SHIPMENT



Revision history STB200N04

6 Revision history

Table 7. Revision history

Date	Revision	Changes
21-Nov-2006	1	First release

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2006 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

